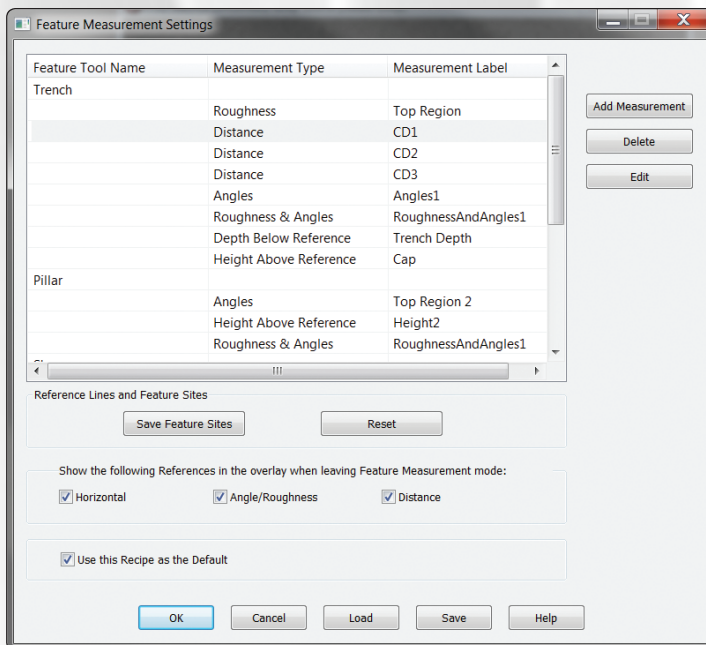


Automated Measurement for Semiconductor Features

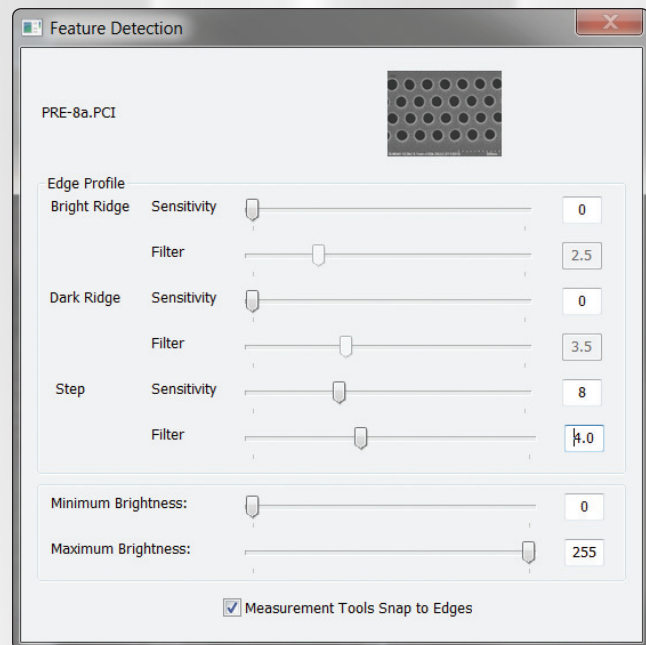
Just Click... and That's it.

3 Levels of 'Single Click' Automation:

1. Fully Characterize a Feature with a Single Click
2. Characterize a Multiple Feature Image with a Single Click Using PCI-AM 'Magic Wand' Tool
3. Use the New PCI-AM Batch Automation to Process and Measure an Entire Folder Similar Images **NEW**



Create and Save Recipes for Measurement Types, Locations and Labels. Load the Recipe for Similar Images.



Our 3 Edge Detection Techniques allow you to work with more types of images and more types of features.

PCI-AM Benefits:

- Save Time
- Increase Measurement Consistency
- Generate Reports Easily with Images and Data
- Increase Measurement Accuracy
- Export Data Easily Into CSV File



QUARTZ IMAGING CORPORATION

SPECIALIZED SOLUTIONS FOR ELECTRONIC DEVICE LABS & ANALYSIS

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**FOR A FASTER
SMARTER LAB**

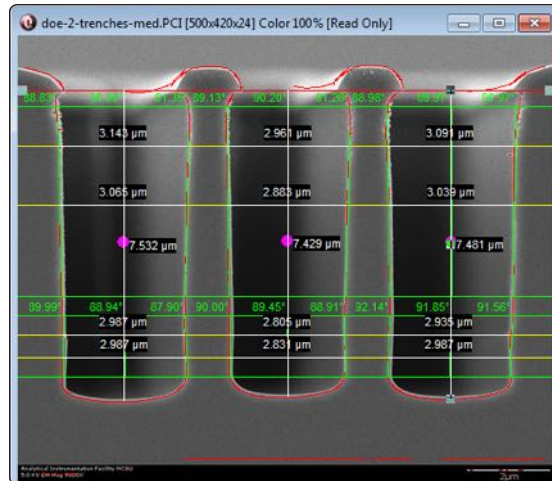
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Automated Measurement for Semiconductor Features

Types of Automated Measurements

Trenches (Spaces) and Pillars (Lines)

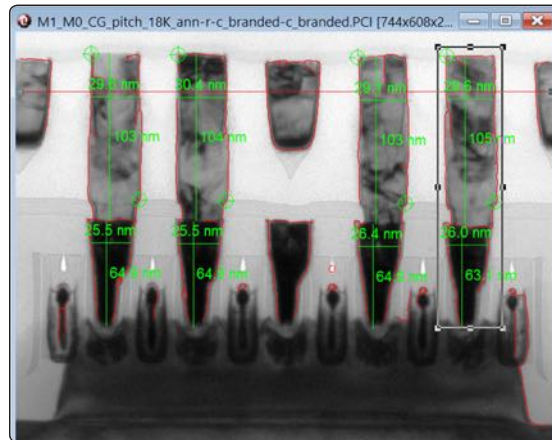
- CD Width
- Angles – Sidewall and Center
 - Multiple Regions in Feature
- Line Edge Roughness
- Line Width Roughness
- Distances Below and Above Reference Line
- Averages of the Above Measurements



Trench Measurements

Macro Cell

- Multiple Measurements in Complex Features with a Single Click



Macro Cell

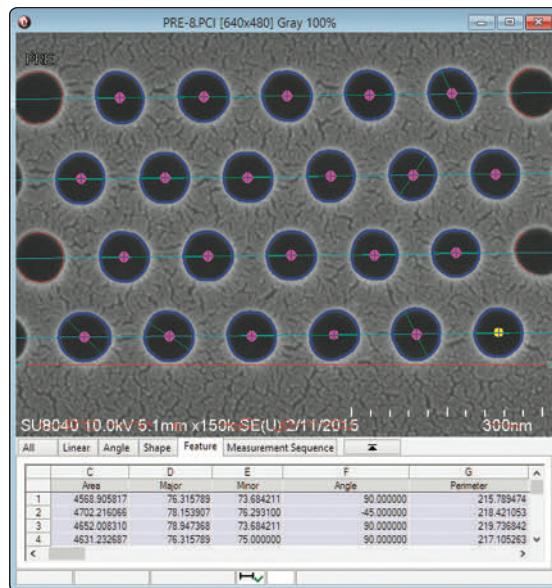
Shapes

- Area and Perimeter
- Ideal Shape Deviation
- Aspect Ratio
- Major and Minor Axes
- Collinearity
- Tilt

Other New Valuable PCI-AM Features

- “Point and Shoot” Horizontal and Vertical Measurement Tools Utilize Edges
- Regular PCI Measurement Tools will “Snap” to the Edges in PCI-AM
- Predetermine the number and exact location of CD measurements relative to the reference line **NEW**
- Improved edge detection capabilities **NEW**

We Can Custom Develop any Specific Measurements You Require.



Shape Measurements